



(51) International Patent Classification:
G01M 11/02 (2006.01) *G01M 11/04* (2006.01)

(21) International Application Number:
PCT/US2024/010332

(22) International Filing Date:
04 January 2024 (04.01.2024)

(25) Filing Language: English

(26) Publication Language: English

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(81) Designated States (unless otherwise indicated, for every kind of national protection available): AE, AG, AL, AM, AO, AT, AU, AZ, BA, BB, BG, BH, BN, BR, BW, BY, BZ, CA, CH, CL, CN, CO, CR, CU, CV, CZ, DE, DJ, DK, DM, DO, DZ, EC, EE, EG, ES, FI, GB, GD, GE, GH, GM, GT, HN, HR, HU, ID, IL, IN, IQ, IR, IS, IT, JM, JO, JP, KE, KG, KH, KN, KP, KR, KW, KZ, LA, LC, LK, LR, LS, LU, LY, MA, MD, MG, MK, MN, MU, MW, MX, MY, MZ, NA, NG, NI, NO, NZ, OM, PA, PE, PG, PH, PL, PT, QA, RO, RS, RU, RW, SA, SC, SD, SE, SG, SK, SL, ST, SV, SY, TH, TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, WS, ZA, ZM, ZW.

(84) Designated States (unless otherwise indicated, for every kind of regional protection available): ARIPO (BW, CV,

(54) Title: OPTICAL PROPERTY MEASUREMENT

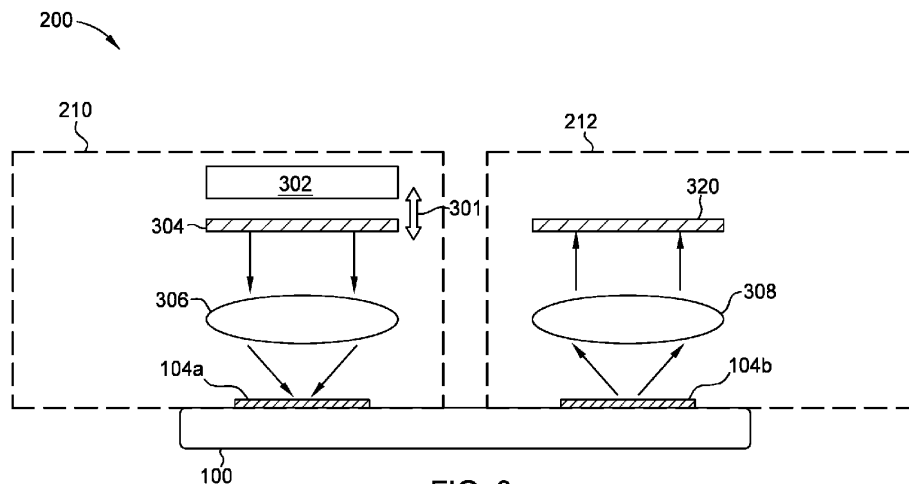


FIG. 3

(57) Abstract: Embodiments herein provide for a measurement system for determining optical properties of an optical device. The measurement system includes a light engine having a light source. The light source is configured to project a light including at least a first wavelength of light, a second wavelength of light, and a third wavelength of light. Reticles are configured to form a pattern from the light projected from the light source. The reticles are configured to be positioned at least in a first position to form a first pattern with the first wavelength of light, a second position to form a second pattern with the second wavelength of light, and a third position to form a third pattern with the third wavelength of light along an axis extending from the light source to a first lens. A detector configured to detect the light from the optical device.

[Continued on next page]

GH, GM, KE, LR, LS, MW, MZ, NA, RW, SC, SD, SL, ST,
SZ, TZ, UG, ZM, ZW), Eurasian (AM, AZ, BY, KG, KZ,
RU, TJ, TM), European (AL, AT, BE, BG, CH, CY, CZ,
DE, DK, EE, ES, FI, FR, GB, GR, HR, HU, IE, IS, IT, LT,
LU, LV, MC, ME, MK, MT, NL, NO, PL, PT, RO, RS, SE,
SI, SK, SM, TR), OAPI (BF, BJ, CF, CG, CI, CM, GA, GN,
GQ, GW, KM, ML, MR, NE, SN, TD, TG).

Published:

— with international search report (Art. 21(3))